Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/812,069	NIIMI ET AL.	
Examiner	Art Unit	
Tran N. Nguyen	2834	

SEARCHED				
Class	Subclass	Date	Examiner	
310	216	7/23/	Pan	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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